

BULT116D

MEDIUM VOLTAGE FAST-SWITCHING NPN POWER TRANSISTOR

- INTEGRATED ANTIPARALLEL COLLECTOR- EMITTER DIODE
- LOW SPREAD OF DYNAMIC PARAMETERS
- MINIMUM LOT-TO-LOT SPREAD FOR RELIABLE OPERATION
- VERY HIGH SWITCHING SPEED

APPLICATIONS:

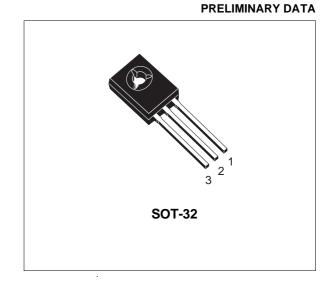
- COMPACT FLUORESCENT LAMPS UP TO 23 W AT 110 V A.C. MAINS
- FLYBACK AND FORWARD SINGLE TRANSISTOR LOW POWER CONVERTERS AT 110 V A.C. MAINS

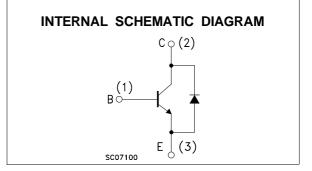
DESCRIPTION

The device is manufactured using Multi Epitaxial Planar technology for high switching speeds and medium voltage capability.

It uses a Cellular Emitter structure with planar edge termination to enhance switching speeds while maintaining the wide RBSOA.

The device is designed for use in lighting applications and low cost switch-mode power supplies.





ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
VCES	Collector-Emitter Voltage (V _{BE} = 0)	400	V
V_{CEO}	Collector-Emitter Voltage $(I_B = 0)$	200	V
V_{EBO}	Emitter-Base Voltage ($I_C = 0$)	9	V
Ι _C	Collector Current	5	A
Ісм	Collector Peak Current (t _p < 5 ms)	10	A
IB	Base Current	2	A
I _{BM}	Base Peak Current (t _p < 5 ms)	4	A
Ptot	Total Dissipation at $T_c = 25 \ ^{\circ}C$	45	W
T _{stg}	Storage Temperature	-65 to 150	°C
Tj	Max. Operating Junction Temperature	150	°C

THERMAL DATA

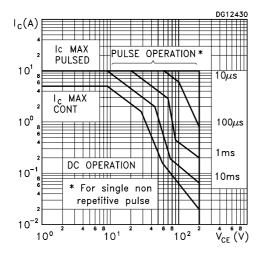
R _{thj-case}	Thermal Resistance Junction-Case	Max	2.78	°C/W
R _{thj-amb}	Thermal Resistance Junction-Ambient	Max	80	°C/W

ELECTRICAL CHARACTERISTICS ($T_{case} = 25 \ ^{\circ}C$ unless otherwise specified)

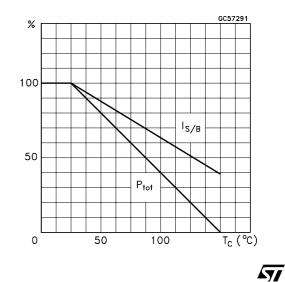
Symbol	Parameter	Test C	onditions	Min.	Тур.	Max.	Unit
I _{CES}	Collector Cut-off Current (V _{BE} = 0)	V _{CE} = 400 V V _{CE} = 400 V	T _c = 125 ^o C			100 500	μΑ μΑ
V_{EBO}	Emitter-Base Voltage (I _C = 0)	I _E = 10 mA		9			V
$V_{CEO(sus)^*}$	Collector-Emitter Sustaining Voltage (I _B = 0)	I _C = 100 mA		200			V
ICEO	Collector Cut-off Current $(I_B = 0)$	V _{CE} = 200 V				250	μA
V _{CE(sat)} *	Collector-Emitter Saturation Voltage	I _C = 0.5 A I _C = 1 A I _C = 3 A I _C = 5 A	I _B = 50 mA I _B = 0.1 A I _B = 0.6 A I _B = 1 A			0.25 0.4 0.7 1.2	V V V V
$V_{BE(sat)^*}$	Base-Emitter Saturation Voltage	$I_{C} = 1 A$ $I_{C} = 5 A$	I _B = 0.1 A I _B = 1 A			1.1 1.5	V V
h _{FE} *	DC Current Gain	I _C = 10 mA I _C = 5 A	V _{CE} = 5 V V _{CE} = 5 V	10 8		20	
t _r t _f t _s	RESISTIVE LOAD Rise Time Fall Time Storage Time	$V_{CC} = 125 V$ $I_{B1} = 0.4 A$ $t_p = 30 \ \mu s$	$I_C = 2 A$ $I_{B2} = -0.4 A$ (see figure 2)		0.2 0.2 1.4	0.4	μs μs μs
t _s t _f	INDUCTIVE LOAD Storage Time Fall Time	$I_{C} = 2 A$ $V_{BE} = -5 V$ $V_{clamp} = 180 V$	I _{B1} = 0.4 A L = 500 μH (see figure 1)		0.5 0.1		μs μs
VF	Diode Forward Voltage	I _C = 2 A				1.5	V

* Pulsed: Pulse duration = 300 μs, duty cycle 1.5 %

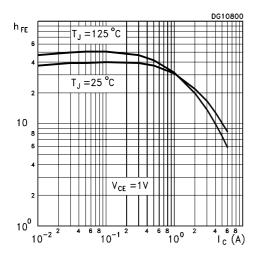
Safe Operating Area



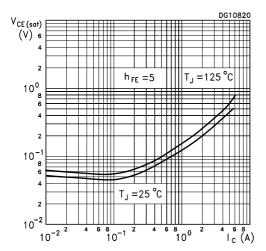
Derating Curve



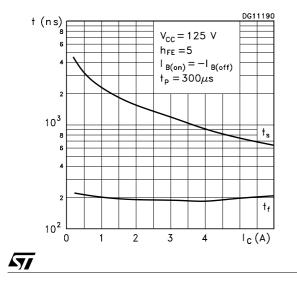
DC Current Gain



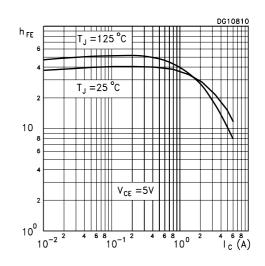
Collector-Emitter Saturation Voltage



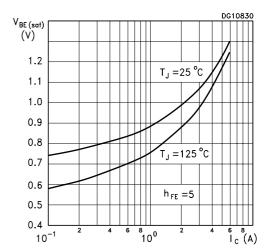
Switching Time Resistive Load

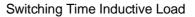


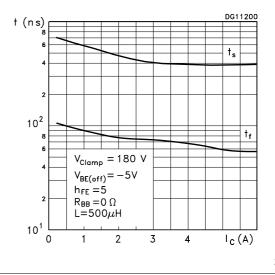
DC Current Gain



Base-Emitter Saturation Voltage







Reverse Biased SOA

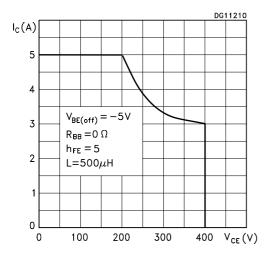


Figure 1: Inductive Load Switching Test Circuit.

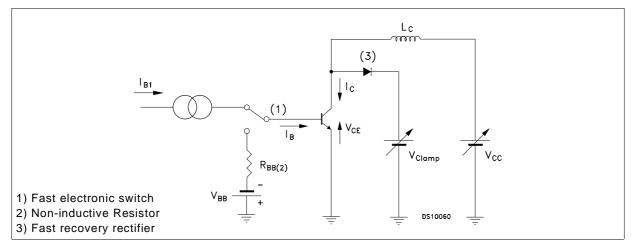
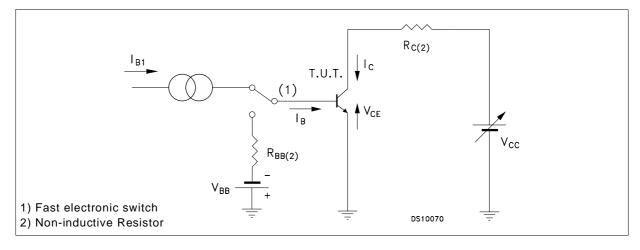


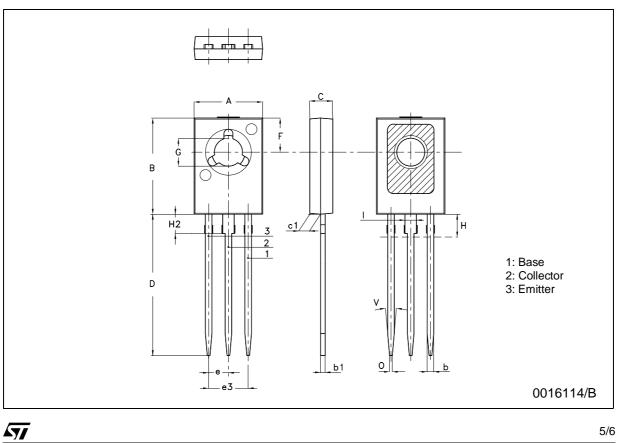
Figure 2: Resistive Load Switching Test Circuit.



57

DIM.	mm			inch			
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	
А	7.4		7.8	0.291		0.307	
В	10.5		10.8	0.413		0.425	
b	0.7		0.9	0.028		0.035	
b1	0.40		0.65	0.015		0.025	
С	2.4		2.7	0.094		0.106	
c1	1.0		1.3	0.039		0.051	
D	15.4		16.0	0.606		0.630	
е		2.2			0.087		
e3		4.4			0.173		
F		3.8			0.150		
G	3		3.2	0.118		0.126	
Н			2.54			0.100	
H2		2.15			0.084		
I		1.27			0.05		
0		0.3			0.011		
V		10 [°]			10 [°]		





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